

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 124421		APPLICATION NO. New U.S. National Stage of PCT/JP03/013725 <div style="font-size: 1.5em; font-weight: bold; margin-top: 10px;">10/541213</div>		
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary) <div style="font-size: 1.5em; font-weight: bold; margin-top: 20px;">6/30/05</div>				APPLICANTS Masaki HIRAKATA et al.		FILING DATE June 30, 2005		GROUP <div style="font-size: 1.5em; font-weight: bold;">2823</div>
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS		
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)								
<div style="font-size: 1.5em; font-weight: bold;">APR</div> <div style="font-size: 1.5em; font-weight: bold;">MAY</div> <div style="font-size: 1.5em; font-weight: bold;">JUN</div> <div style="font-size: 1.5em; font-weight: bold;">JUL</div> <div style="font-size: 1.5em; font-weight: bold;">AUG</div>	1	TSUKAKOSHI et al., "Fundamentals of Conductive Characteristics of Multiwall Carbon Nanotube," <i>Applied Physics</i> , vol. 72, pp. 333-337 {2003} w/ Appendix						
	2	DAI et al., "Controlled Chemical Routes to Nanotube Architectures, Physics, and Devices," <i>J. Phys. Chem.</i> , vol. 103, pp. 11246-11255 {1999}						
	3	CASSELL et al., "Directed Growth of Free-Standing Single-Walled Carbon Nanotubes," <i>J. Am. Chem. Soc.</i> , vol. 121, pp. 7975-7976 {1999}						
	4	SNOW et al., "Random Networks of Carbon Nanotubes as an Electronic Material," <i>Applied Physics Letters</i> , vol. 82, no. 13, pp. 2145-2147 {March 31, 2003}						
	5	LYUBCHENKO et al., "Atomic Force Microscopy of DNA and Bacteriophage in Air, Water and Propanol: The Role of Adhesion Forces," <i>Nucleic Acids Research</i> , vol. 21, no. 5, pp. 1117-1123 {1993}						
EXAMINER	<div style="font-size: 1.5em; font-weight: bold;">Mabelle Estrada</div>				DATE CONSIDERED <div style="font-size: 1.5em; font-weight: bold;">1/2/08</div>			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 124421		APPLICATION NO. 10/541,213	
<b>INFORMATION DISCLOSURE STATEMENT</b> (Use several sheets if necessary)				APPLICANTS Masaki HIRAKATA et al.			
9/13/05							
				FILING DATE June 30, 2005		GROUP 2823	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
<i>me</i> <i>me</i>	1	US 6,342,276 B1	1/29/2002	YOU			
	2	US 2002/0172639 A1	11/21/2002	HORIUCHI et al.			
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
<i>me</i> <i>me</i>	3	WO 01/07694 A1	2/1/2001	WIPO			
	4	JP A 2002-190247 w/ abst & transl	7/5/2002	JAPAN			
	5	WO 01/20402 A1	3/22/2001	WIPO			
	6	EP 1 020 888 A1	7/19/2000	EUROPE			
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
EXAMINER <i>A. Michelle Estrada</i>					DATE CONSIDERED <i>1/2/08</i>		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: September 13, 2005

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 124421		APPLICATION NO. 10/541,213	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)				APPLICANT(S) Masaki HIRAKATA et al.  FILING DATE June 30, 2005			
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
/ME/	1	2002/0122765 A1	09/05/2002	Horiuchi et al.			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
/ME/	2	EP 1 096 533 A1	08/07/2000	European Patent Office			
/ME/	3	WO 02/16257 A2	02/28/2002	PCT			
/ME/	4	JP-A-2002-234000	08/20/2002	Japan	X	X	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER				DATE CONSIDERED			
/Michelle Estrada/				01/06/2008			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: January 4, 2008